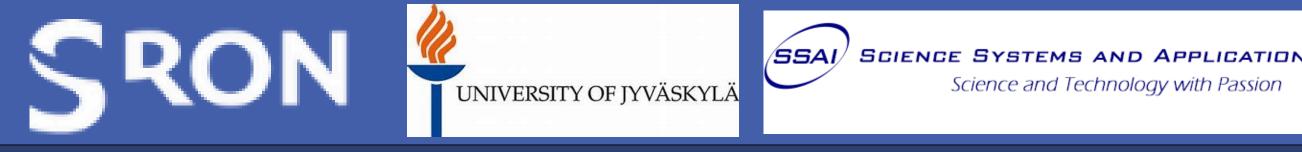


^aNASA Goddard Space Flight Center, Greenbelt MD USA, ^bNIST Gaithersburg MD USA, ^cUniversity of Jyvaskyla Department of Physics, Finland ^dNetherlands Institute for Space Research SRON, Utrecht Netherlands, ^eScience Systems and Applications, Lanham, MD USA

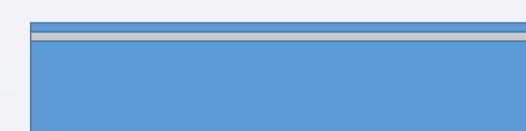




Introduction

- Kinetic inductance detectors provide several characteristics making them a compelling detector choice for astrophysical applications including scalability to large format arrays.
- Photon noise limited sub-mm/far-IR cold telescopes in space will require detectors with noise equivalent power (NEP) less than 1x10⁻¹⁹ W/Hz^{1/2} for imaging applications and spectroscopic studies.

Fabrication Process

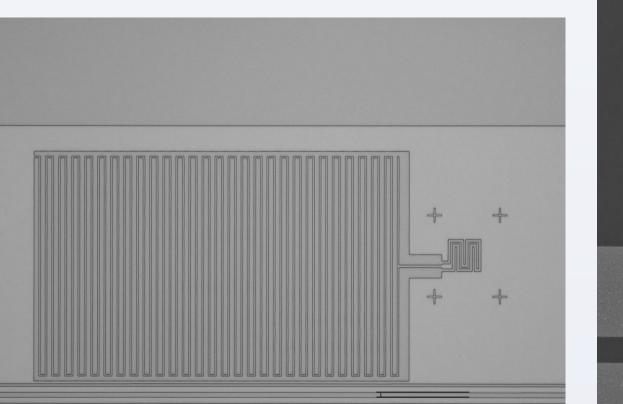


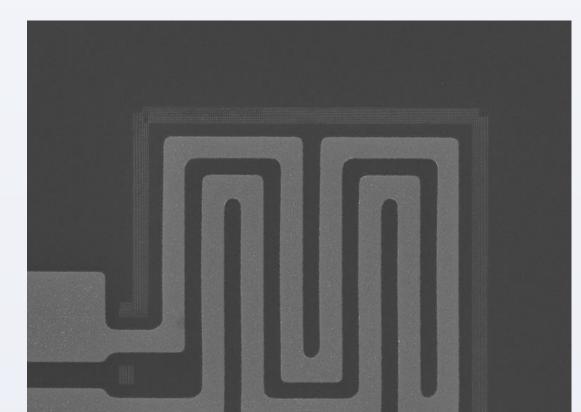
Silicon on insulator wafer with 90 nm thick device layer



Pattern phononic features using electron beam lithography. Etch into the device layer and stop on the buried oxide.

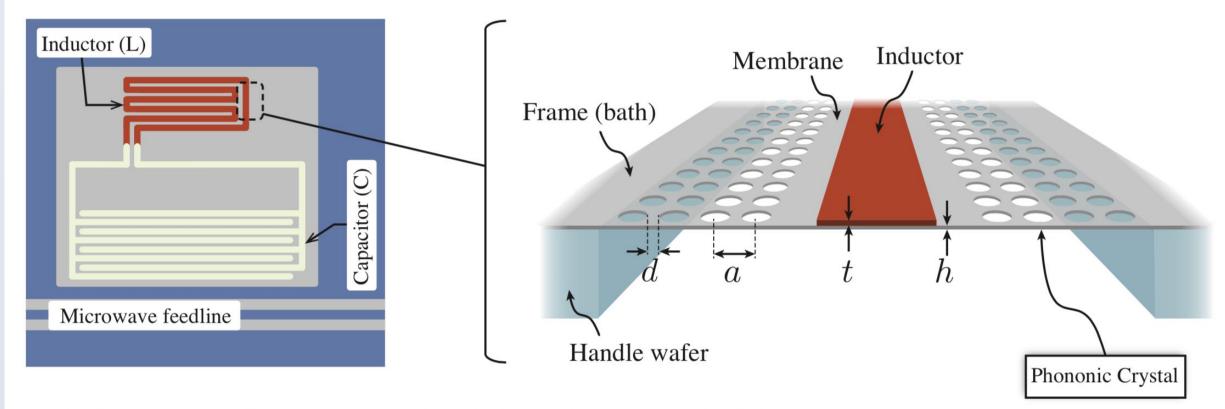
Fabrication Results Electron Beam lithography





- We describe the fabrication of enhanced responsivity KIDs through the incorporation of a phononic crystal choke, which suppresses the flux of recombination and a-thermal (hot) phonons from the superconducting film to the thermal bath.
- The phononic filters are created by etching quasi-periodic nanoscale structures into a silicon membrane which isolates the KID inductor from the thermal bath.
- The phonon transmission of the phononic crystal is unity for thermal wavelength phonons, thus preventing the formation of a thermal kinetic inductance detector.

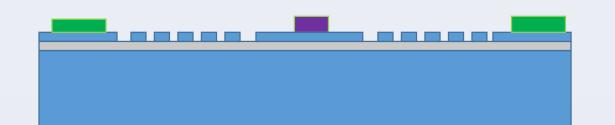
Design Approach



* Phononic crystal pattern encapsulates inductor (see text for details) ** Inductor is low- T_c superconducting thin-film, e.g. Hf ($T_c \sim 400$ mK) *** Capacitor is high- T_c superconducting thin-film, e.g. Nb ($T_c \sim 9$ K)



Pattern niobium CPW feed line and capacitor using laser lithography, sputter deposit and liftoff the niobium layer.



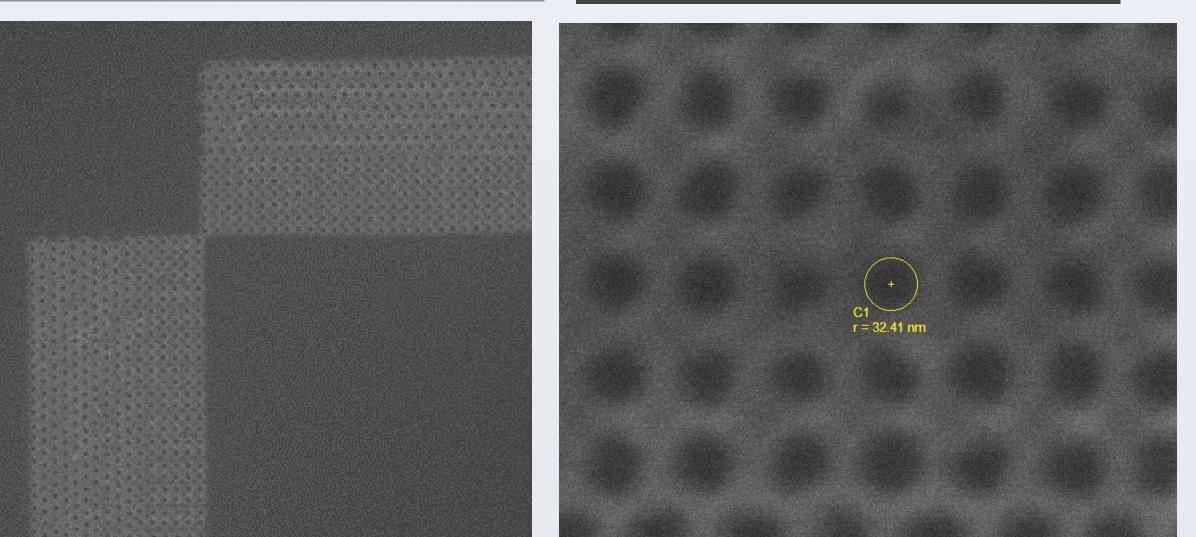
Pattern hafnium inductor using laserlithography, sputter deposit and liftoff thehafnium layer.

Bond wafer with wax to a handle wafer (not shown). Pattern handle wafer side of silicon wafer and deep reactive ion etch to create membrane. Remove handle wafer by dissolving wax.

Simplified fabrication scheme for phononic isolated kinetic inductance detectors

Material	Thickness [nm]	Process	
Niobium	50	DC Sputter	Liftoff PMGI S1805
Hafnium	65	DC Sputter	Liftoff PMGI,S1805
Gold heat sink / heater	300	Electron beam evaporation	Lift-off PMGI in acetone
Si membrane	90	LPCVD	Etch: SF ₆ /CHF ₃ at 100 W, 20 mT
SiO ₂ etch stop	300	Thermal Oxidation	Buffered HF (7:1)
Silicon	300 (um)	Deep Reactive Ion Etch	BOSCH SF ₆ , C ₄ F ₈

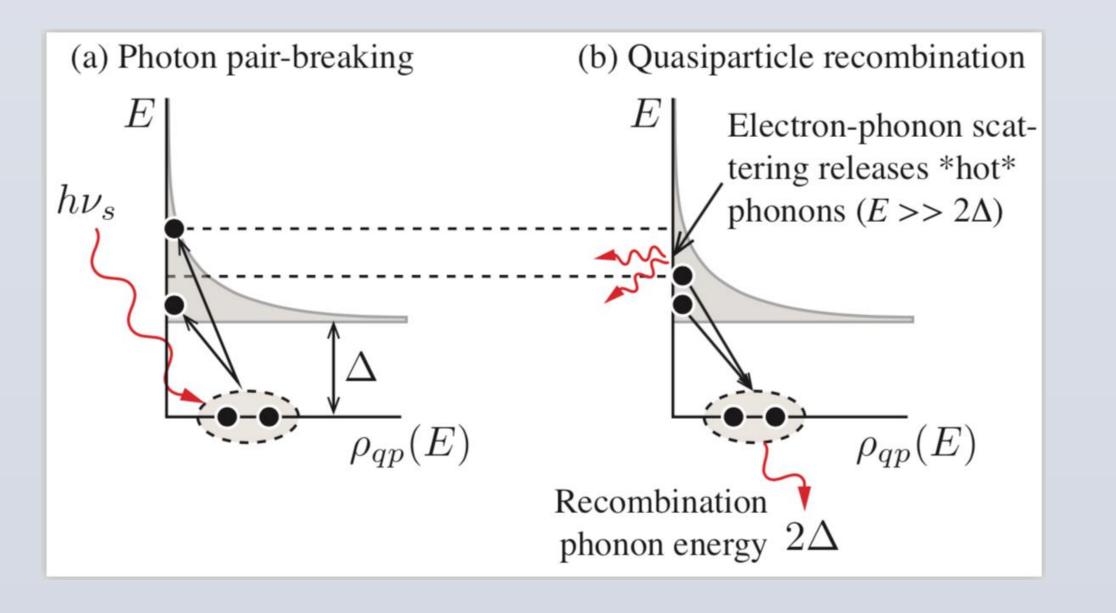
24: 4.68 μm



SEM micrographs of etched silicon phononic structures. The silicon is patterned using ZEP 520 resist spun at 2500 rpm. The resist is exposed with a JEOL JBX-6300 at 100kV with 520 μ C/cm² dose. The features are designed as 45 nm squares to result in approximately 64 nm diameter circles as fabricated holes. The phononic structures are on a 110 nm pitch consisting of both hexagonal and square tiling.

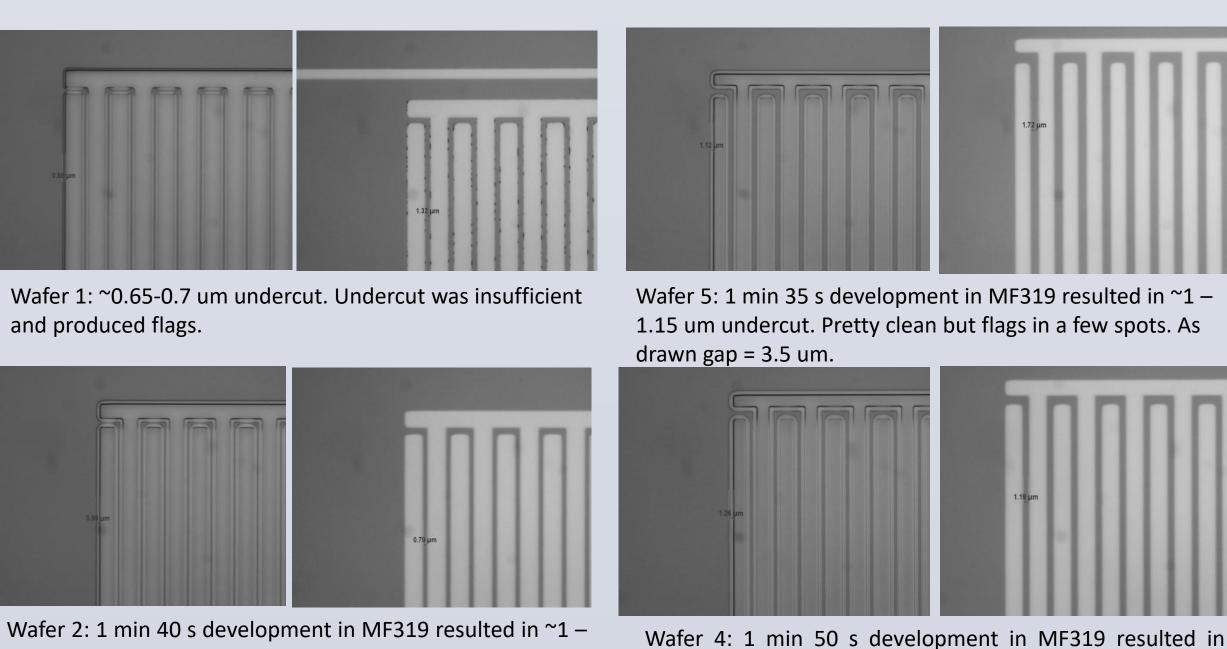
Conclusions

A phononic crystal matched to a superconducting resonator (or MKID) will increase the number of recombination and a-thermal phonons in the superconducting film. The result is increased responsivity to electromagnetic radiation.



The energy resolution of state-of-the-art photon counting KIDs is nearly an order of magnitude below the statistical (Fano) limit for a pair-breaking device. We have added a meta-material phononic crystal that reduces the loss of recombination and aMaterial thicknesses and process information. A similar process could be achieved using SiN/SiO_x coated wafers

Fabrication Results – Laser lithography



Wafer 2: 1 min 40 s development in MF319 resulted in \sim 1 – 1.15 um undercut. Pretty clean but flags in a few spots. Delamination occurring b/c 2.5um gap too small to support resist.

- A fabrication process mixing direct write laser, contact, and electron beam lithography was developed to integrate a phononic filter into a KID geometry.
- We have developed a new liftoff process using direct write laser based lithography enabling 1 µm spaces in sputtered Nb and Hf films.
- Electron beam lithography and etching with minimum features of 65 nm has been demonstrated which is close to our 60 nm requirement.
- The new process incorporates a Nb microwave feedlines with a Hf inductor deposited by a DC sputtering process with Tc of 430 mK, Ls = 28pH/sq. Internal quality factor greater than 10^5 has been measured.

References

[1] "Enhanced Quasiparticle Lifetime in a Superconductor by Selective Blocking of Recombination Phonons with a Phononic Crystal", K. Rostem, P.J. de Visser, E.J. Wollack, Physical Review B, 98 014522 (2018)

[2] . "Superconducting microresonators: Physics and applications.", J. Zmuidzinas, Annu. Rev. Condens. Matter Phys., 3(1):169-214, 2012.

[3] "Counting near infrared photons with microwave kinetic inductance detectors." W. Guo, X. Liu, Y. Wang, Q. Wei, L. F. Wei, J. Hubmayr, J. Fowler, J. Ullom, L. Vale, M. R. Vissers, and J. Gao. Applied Physics Letters, 110(21):212601, 2017.

thermal phonons from a KID. The phononic crystal:

- increases the responsivity of the MKID to signal photons,
 reduces the NEP due to quasiparticle generationrecombination (GR) noise, and
- (3) reduces the loss of a-thermal phonons to the detector substrate, directly impacting the energy-resolving power of an optical/NIR KID.

A bilayer of LOR-5A/S1805 resist is used for laser lithography exposed in a Heidelberg DWL 66+ using the high resolution write head with minimum features sizes of 0.3 μ m. It was found that to avoid "flags" a minimum of 1.25 μ m undercut is required. To achieve a 1 um gap between lines, an as drawn gap of 3 μ m is required which leaves 0.5 μ m of resist for structural support.

~1.25 um undercut. No flags observed. Initial 3um gap

between lines results in close to 1 um as fabricated gap.

[4] "Generation-recombination noise: The fundamental sensitivity limit for kinetic inductance detectors." P. J. de Visser, J. J. A. Baselmans, P. Diener, S. J. C. Yates, A. Endo, and T. M. Klapwijk. Journal of Low Temperature Physics, 167(3):335-340, May 2012.

Contact & Acknowledgements

- *Kevin L. Denis, kevin.l.denis@nasa.gov; phone 1-301-286-7935; fax 301-286-1672; nasa.gov
- Goddard Space Flight Center Internal Research and Development Programs

RESEARCH POSTER PRESENTATION DESIGN © 2015 www.PosterPresentations.com